74ACT11593 8-BIT BINARY COUNTER WITH PARALLEL-INPUT REGISTERS AND 3-STATE OUTPUTS SCAS203 – JUNE 1992 – REVISED APRIL 1993

Counter/3-State OutputsA/QA124CCK• Counter Has Direct Overriding Load and ClearB/QB223CCK• Flow-Through Architecture Optimizes PCB LayoutD/QD421CCKEN• Center-Pin V _{CC} and GND Configurations Minimize High-Speed Switching NoiseGND619V _{CC} • EPIC™ (Enhanced-Performance Implanted CMOS) 1-µm ProcessGND817OE• 500-mA Typical Latch-Up Immunity at 125°CF/QF1015RCK• Package Options Include PlasticH/QH1213RCO	 Inputs Are TTL-Voltage Compatible Parallel Register Inputs/Binary 	DW OR NT PACKAGE (TOP VIEW)
 Counter Has Direct Overriding Load and Clear Flow-Through Architecture Optimizes PCB Layout Counter Pin V_{CC} and GND Configurations Minimize High-Speed Switching Noise Counter Pin V_{CC} and GND Configurations Minimize High-Speed Switching Noise Counter Pin V_{CC} and GND Configurations Minimize High-Speed Switching Noise Counter Pin V_{CC} and GND Configurations Minimize High-Speed Switching Noise Counter Pin V_{CC} and GND Configurations Minimize High-Speed Switching Noise Counter Pin V_{CC} and GND Configurations Minimize High-Speed Switching Noise Counter Pin V_{CC} and GND Configurations Minimize High-Speed Switching Noise Counter Pin V_{CC} and GND Configurations Minimize High-Speed Switching Noise Counter Pin V_{CC} and GND Configurations Minimize High-Speed Switching Noise Counter Pin V_{CC} and GND Configurations Minimize High-Speed Switching Noise Counter Pin V_{CC} and GND Configurations Minimize High-Speed Switching Noise Counter Pin V_{CC} and GND Configurations Minimize High-Speed Switching Noise Counter Pin V_{CC} and GND Configurations Minimize High-Speed Switching Noise Counter Pin V_{CC} and GND Configurations Minimize High-Speed Switching Noise Counter Pin V_{CC} and GND Configurations Minimize High-Speed Switching Noise Counter Pin V_{CC} and GND Configurations Minimize High-Speed Switching Noise Counter Pin V_{CC} and GND Configurations Minimize High-Speed Switching Noise Counter Pin V_{CC} and GND Configurations Minimize High-Speed Switching Noise Counter Pin V_{CC} and GND Configurations Counter Pin V_{CC} and G		
Clear C/Q_C 322CCKEN• Flow-Through Architecture Optimizes PCB Layout D/Q_D 421CCKEN• Center-Pin V _{CC} and GND Configurations Minimize High-Speed Switching NoiseGND520CLOAD• EPIC TM (Enhanced-Performance Implanted CMOS) 1-µm ProcessGND817OE• 500-mA Typical Latch-Up Immunity at 125°C F/Q_F 1015RCK• Package Options Include Plastic H/Q_H 1213RCO	 Counter Has Direct Overriding Load and 	
PCB LayoutGND520CLOAD• Center-Pin V _{CC} and GND Configurations Minimize High-Speed Switching NoiseGND619V _{CC} • EPIC TM (Enhanced-Performance Implanted CMOS) 1-µm ProcessGND8170E• 500-mA Typical Latch-Up Immunity at 125°C F/Q_F 1015RCK• Package Options Include Plastic H/Q_H 1213RCO	Clear	P 7 F
 Center-Pin V_{CC} and GND Configurations Minimize High-Speed Switching Noise <i>EPIC</i>[™] (Enhanced-Performance Implanted CMOS) 1-µm Process 500-mA Typical Latch-Up Immunity at 125°C Package Options Include Plastic GND [6 19] V_{CC} GND [7 18] V_{CC} GND [7 18] V_{CC} GND [7 18] V_{CC} GND [8 17] OE F/Q_E [9 16] OE F/Q_F [10 15] RCK G/Q_G [11 14] RCK H/Q_H [12 13] RCO 		E
Minimize High-Speed Switching Noise GND [] 7 18 V _{CC} ● EPIC [™] (Enhanced-Performance Implanted CMOS) 1-µm Process GND [] 8 17 OE ● 500-mA Typical Latch-Up Immunity at 125°C F/Q _F [] 10 15 RCK ● Package Options Include Plastic H/Q _H [] 12 13 RCO	PCB Layout	3 6
 <i>EPIC</i>[™] (Enhanced-Performance Implanted CMOS) 1-µm Process 500-mA Typical Latch-Up Immunity at 125°C Package Options Include Plastic GND [] 8 17] OE E/QE [] 9 16] OE F/QF [] 10 15] RCK G/QG [] 11 14] RCK H/QH [] 12 13] RCO 		
• EPIC (Enhanced-Performance implanted CMOS) 1- μ m Process • 500-mA Typical Latch-Up Immunity at 125°C • Package Options Include Plastic • L/Q _E $\begin{bmatrix} 9 & 16 \\ 0 & 15 \\ 10 & 15 \\ 0 & CK \\ G/Q_G \begin{bmatrix} 1 & 14 \\ 11 & 14 \end{bmatrix} RCK$	Minimize High-Speed Switching Noise	
• 500-mA Typical Latch-Up Immunity at 125°C • Package Options Include Plastic $F/Q_F \begin{bmatrix} 1 & 15 \\ 11 & 14 \end{bmatrix} \frac{1}{RCK}$ $H/Q_H \begin{bmatrix} 12 & 13 \\ 12 & 13 \end{bmatrix} \frac{1}{RCK}$	 EPICTM (Enhanced-Performance Implanted 	
Sou-ma Typical Latch-Op Immunity at 125°C G/Q _G [] 11 14 [] RCK H/Q _H [] 12 13 [] RCO	CMOS) 1-µm Process	
• Package Options Include Plastic	• 500-mA Typical Latch-Up Immunity at 125°C	· 3
Plastic 300-mil DIPs	Small-Outline Packages and Standard	

description

The 74ACT11593 contains eight multiplexed parallel I/Os with 3-state output capability and an 8-bit storage register that feeds an 8-bit binary counter. Both the register and the counter have individual positive-edge triggered clocks.

The function tables show the operation of the counter clock-enable (CCKEN, $\overline{\text{CCKEN}}$) and output-enable (OE, $\overline{\text{OE}}$) inputs.

The counter input has direct load and clear functions. A low-going RCO pulse is obtained when the counter reaches the hex word FF.

Expansion is easily accomplished for two stages by connecting RCO of the first stage to CCKEN of the second stage. Cascading for larger count chains is accomplished by connecting RCO of each stage to CCK of the following stage.

The 74ACT11593 is characterized for operation from -40°C to 85°C.

COUNTER CLOCK ENABLE							
INP	UTS	OUTPUTS					
CCKEN	CCKEN	A/Q _A THRU H/Q _H					
L	L	Disable					
L	Н	Disable					
Н	L	Enable					
Н	Н	Disable					

Function Tables

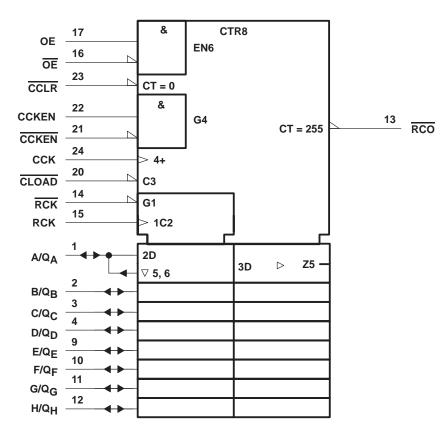
OUTPUT ENABLE					
INP	UTS	OUTPUTS			
OE	OE	A/Q _A THRU H/Q _H			
L	L	Input mode			
L	Н	Input mode			
н	L	Output mode			
н	Н	Input mode			

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logic symbol[†]



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.



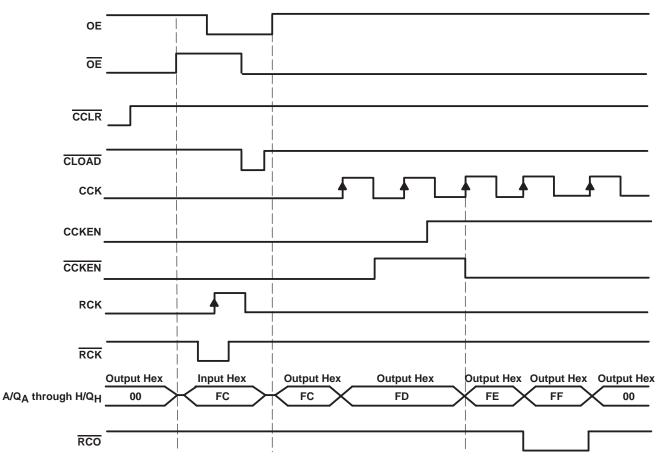
0E <u>17</u> <u>OE</u> <u>16</u> CCLR 23 -0 CCKEN 22 13 RCO CCKEN 21 сск -24 20 CLOAD RCK 14 RCK 15 A/QA 1 1D S > T C1 R B/QB 1D s ⊳T - C1 R C/QC 3 1D s > T - C1 R D/QD 4 1D S ⊳ **т** > C1 R E/Q_E 9 1D S **>т C1** R F/Q_F 10 ◀ 1D S > T > C1 R G/Q_G ¹¹ ◀ 1D s > T > C1 R 1D s о⊳т - C1 R

logic diagram (positive logic)



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typical operating sequence



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V _{CC}	–0.5 V to 7 V
Input voltage range, V _I (see Note 1)	$\dots \dots \dots -0.5 \text{ V to V}_{CC} + 0.5 \text{ V}$
Output voltage range, V _O (see Note 1)	$\dots \dots \dots -0.5 \text{ V to V}_{CC} + 0.5 \text{ V}$
Input clamp current, I _{IK} (V _I < 0 or V _I > V _{CC})	±20 mA
Output clamp current, I_{OK} ($V_O < 0$ or $V_O > V_{CC}$)	±50 mA
Continuous output current, $I_O (V_O = 0 \text{ to } V_{CC})$	±50 mA
Continuous current through V _{CC} or GND	±225 mA
Storage temperature range	

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: The input and output voltage ratings may be exceeded if the input and output clamp-current ratings are observed.



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recommended operating conditions (see Note 2)

		MIN	NOM	MAX	UNIT
VCC	Supply voltage	4.5	5	5.5	V
V_{IH}	High-level input voltage	2			V
$V_{ L}$	Low-level input voltage			0.8	V
VI	Input voltage	0		VCC	V
VO	Output voltage	0		VCC	V
IOH	High-level output current			-24	mA
IOL	Low-level output current			24	mA
$\Delta t/\Delta v$	Input transition rise or fall rate	0		10	ns/V
Т _А	Operating free-air temperature	-40		85	°C

NOTE 2: Unused or floating inputs must be held high or low.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

	TEST CONDITIONS	v _{cc}	T _A = 25°C					
PARAMETER	TEST CONDITIONS		MIN	TYP	MAX	MIN	MAX	UNIT
		4.5 V	4.4			4.4		
	I _{OH} = -50 μA	5.5 V	5.4			5.4		
∨он		4.5 V	3.94			3.8		V
	I _{OH} = -24 mA	5.5 V	4.94			4.8		
	$I_{OH} = -75 \text{ mA}^{\dagger}$	5.5 V				3.85		
	I _{OL} = 50 μA				0.1		0.1	
					0.1		0.1	
VOL		4.5 V			0.36		0.44	4 V
	I _{OL} = 24 mA				0.36		0.44	
	$I_{OL} = 75 \text{ mA}^{\dagger}$	5.5 V					1.65	
Ц	V _I = V _{CC} or GND	5.5 V			±0.1		±1	μΑ
IOZ	$V_{O} = V_{CC}$ or GND	5.5 V			±0.5		±5	μΑ
ICC	$V_I = V_{CC} \text{ or } GND, \qquad I_O = 0$	5.5 V			8		80	μΑ
∆I _{CC} ‡	One input at 3.4 V, Other inputs at V_{CC} or GND	5.5 V			0.9		1	mA
Ci	$V_I = V_{CC}$ or GND	5 V		3.5				pF
C _{io}	$V_{O} = V_{CC}$ or GND	5 V		12.5				pF

[†] Not more than one output should be tested at a time, and the duration of the test should not exceed 10 ms.

[‡]This is the increase in supply current for each input that is at one of the specified TTL voltage levels rather than 0 V or V_{CC}.



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timing requirements over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V (unless otherwise noted) (see Figure 1)

			T _A = 2	T _A = 25°C		A = 25°C			
			MIN	MAX	MIN	MAX	UNIT		
fclock	Clock frequency, CCK or RCK			52		52	MHz		
		CCK high or low	9.6		9.6				
	Dulas duration	RCK high or low	5.8		5.8				
tw	Pulse duration	CCLR low	7.6		7.6		ns		
		CLOAD low	6.2		6.2				
	Setup time	CCKEN low before CCK [↑]	3.6		3.6		ns		
		CCKEN high before CCK↑	4		4				
		CCLR high before CCK↑	1.2		1.2				
t _{su}		CLOAD high before CCK [↑]	5.1		5.1				
		RCK [↑] before CLOAD ^{↑†}	7.4		7.4				
		Data A thru H before RCK↑	2.4		2.4				
	Lold time	Data A thru H after RCK↑	1.2		1.2				
^t h	Hold time	All others	0.8		0.8		ns		

switching characteristics over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V (unless otherwise noted) (see Figure 1)

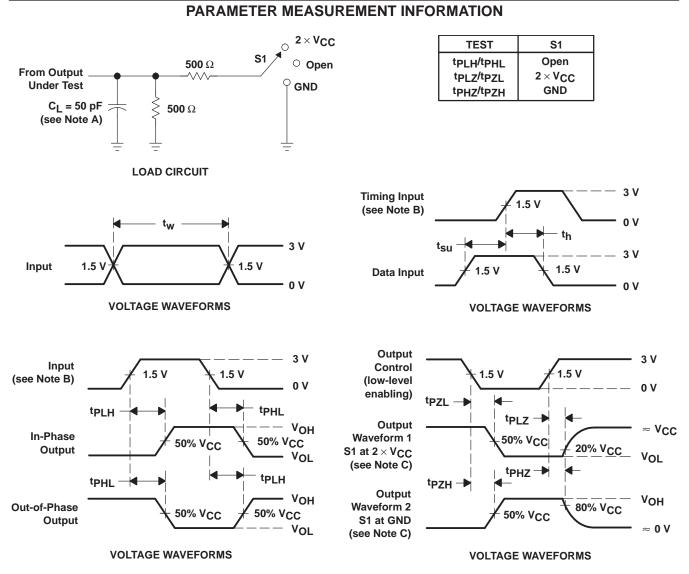
	FROM	то	TO T _A = 25°C		;			
PARAMETER	(INPUT)	(OUTPUT)	MIN	TYP	MAX	MIN	MAX	UNIT
f _{max}			52			52		MHz
^t PLH	001/	0	5.6	10.2	13.3	5.6	15.1	
^t PHL	CCK	Q	5.8	10.3	13.3	5.8	15	ns
^t PLH	CLOAD	0	5.5	12	16.9	5.5	19.1	20
^t PHL		Q	5.8	13.5	19.4	5.8	21.7	ns
^t PHL	CCLR	Q	5	10.4	14.3	5	16	ns
^t PZH	05	0	5.9	10.9	14.3	5.9	16.3	
^t PZL	OE	Q	5.9	11.1	14.8	5.9	16.9	ns
^t PZH	ŌĒ		4.9	10.4	14.4	4.9	16.5	
^t PZL		Q	5.1	10.7	15	5.1	17	ns
^t PHZ	05		5.3	9	11.8	5.3	12.9	
^t PLZ	OE	Q	6.2	10.2	13.1	6.2	14.4	ns
^t PHZ	OE		5.6	8.6	10.7	5.6	11.6	
^t PLZ	OE	Q	6.4	9.9	12	6.4	13.3	ns
^t PLH	CCK	RCO	4.9	9.2	12.1	4.9	13.7	20
^t PHL	ССК	RCO	5.8	10.9	14.3	5.8	16.3	ns
^t PLH	CLOAD	RCO	4.6	9.6	13.3	4.6	15	
^t PHL	CLOAD		7.1	13.6	18.5	7.1	21	ns
^t PLH	CCLR	RCO	5.1	10.3	14.5	5.1	16.2	ns
^t PLH	RCK	RCO	6.7	12	15.6	6.7	17.7	ns
^t PHL	NOK	RCO	7.5	13.6	17.8	7.5	20.2	115



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operating characteristics, V_{CC} = 5 V, T_A = 25°C

	PARAMETER			TEST CONDITIONS		
		Outputs enabled	0 50 - 5		61	
Cpd	Power dissipation capacitance	Outputs disabled	C _L = 50 pF,	f = 1 MHz	15	pF



- NOTES: A. CI includes probe and jig capacitance.
 - B. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, Z_O = 50 Ω , t_f = 3 ns, t_f = 3 ns.
 - C. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - D. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



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